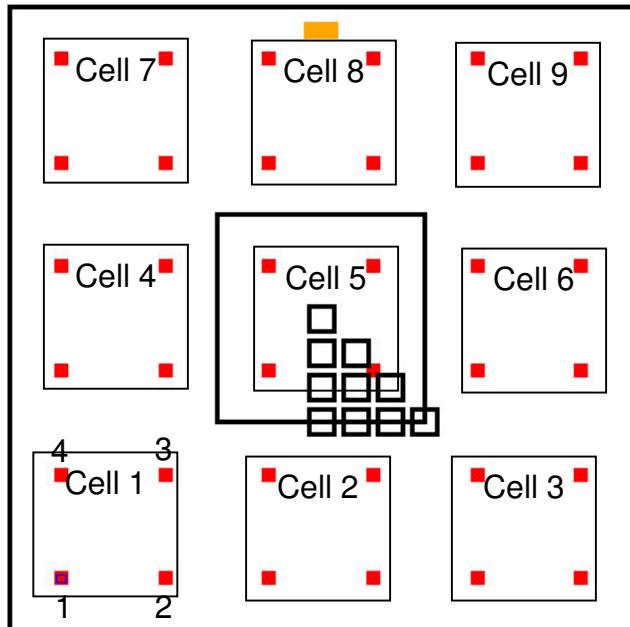


CALICE D4 simulation results

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Cell size: $25 \times 25 \mu\text{m}^2$

Epitaxial thickness: $20 \mu\text{m}$

Diode location: S4

Diode size: $1.5 \times 1.5 \mu\text{m}^2$

Cell := enclosing of 4 diodes whose Charge add (as in cell 5)

Diode bias: 2V

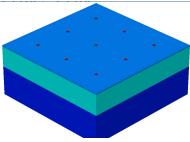
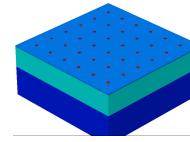
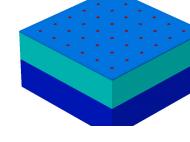
PWell bias: 0V

Substrate bias: floating

10 hits simulated: mirroring over central cell and transformation over 3×3 cells allows surface reconstruction of $Q_{\text{coll}}(x,y)$

CALICE D4 simulation results

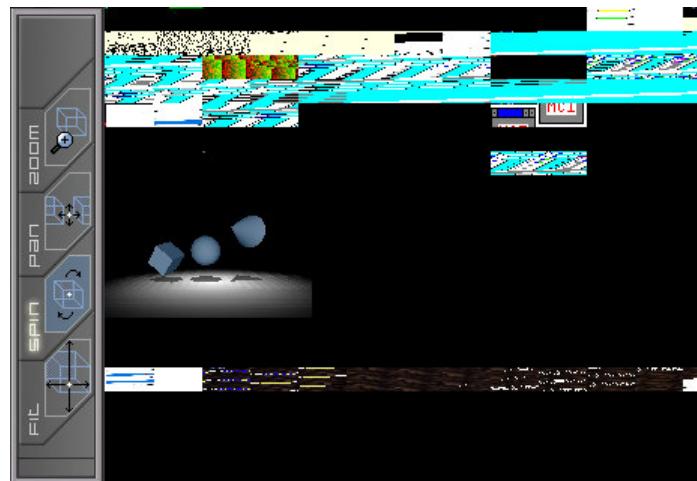
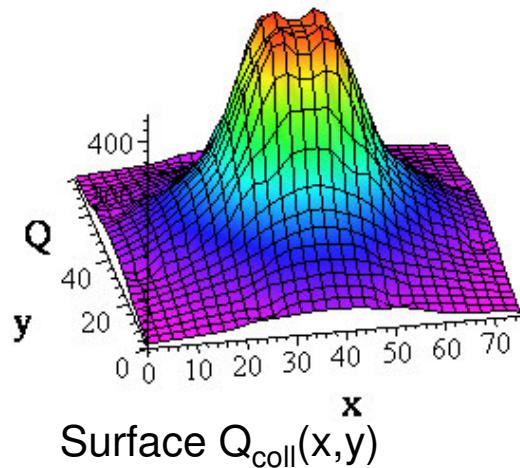
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thickness	single	multi
15 μm	 	 
20 μm		 

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Epitaxial thickness: 20 μm



Normalized surface $Q_{\text{coll}}(x,y)$ vs. $\max(Q_{\text{coll}}(x,y))$

4	10	15	15	10	4
10	26	43	42	25	10
15	44	105	106	43	15
15	44	105	106	44	15
10	26	44	44	26	10
4	10	15	15	10	4

Single diode $Q_{\text{coll}}(x,y)$ hit 1

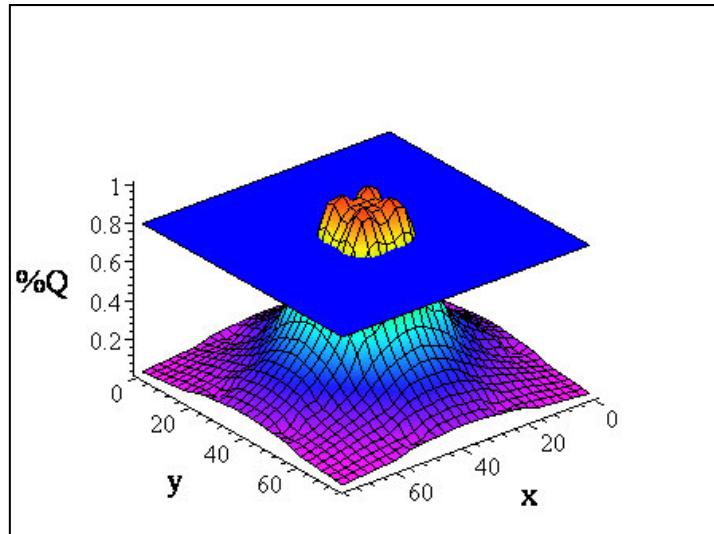
50	116	49
118	422	118
51	118	50

Sum diode $Q_{\text{coll}}(x,y)$ hit 1

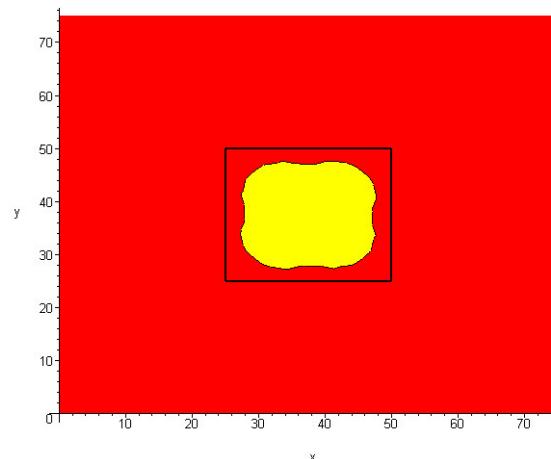
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Epitaxial thickness: 20 μm



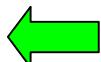
Normalized surface $Q_{\text{coll}}(x,y)$ vs.
 $\max(Q_{\text{coll}}(x,y))$



Contour plot of cell charge at different % of
total collected charge

Increasing number of threshold levels reduces spatial error

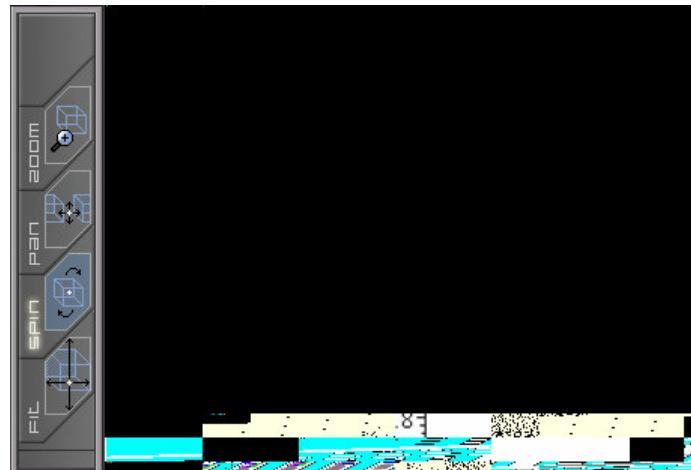
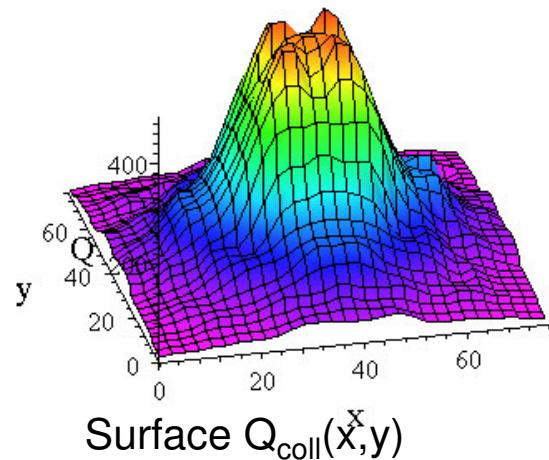
Minimum error around $\approx 57\%$ (need further analysis)



CALICE D4 simulation results

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Epitaxial thickness: 15 μm



Normalized surface $Q_{\text{coll}}(x,y)$ vs. $\max(Q_{\text{coll}}(x,y))$

4	9	17	19	10	7
9	24	45	45	25	9
14	41	115	119	44	14
14	41	110	113	43	14
8	23	40	40	30	9
3	8	23	18	10	5

Single diode $Q_{\text{coll}}(x,y)$ hit 1

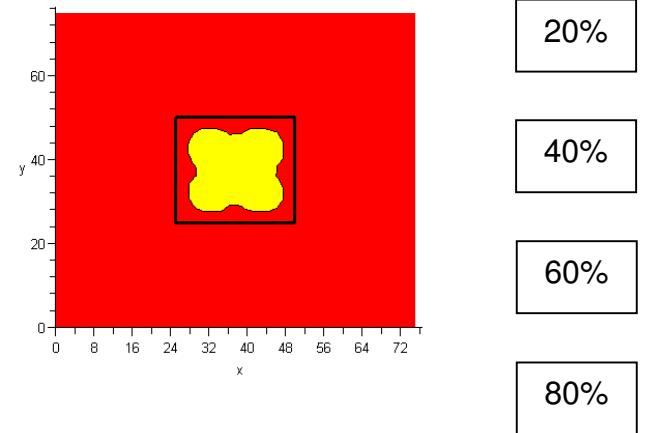
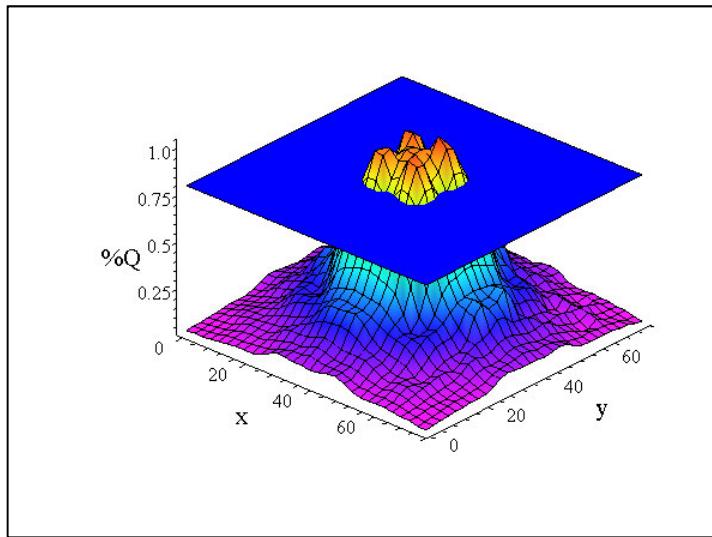
46	126	51
110	457	115
43	121	53

Sum diode $Q_{\text{coll}}(x,y)$ hit 1

CALICE D4 simulation results

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Epitaxial thickness: 15 μm

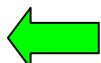


Contour plot of cell charge at different % of total collected charge

Normalized surface $Q_{\text{coll}}(x,y)$ vs.
 $\max(Q_{\text{coll}}(x,y))$

Increasing number of threshold levels reduces spatial error

Minimum error around $\approx 57\%$ (need further analysis)



CALICE D4 simulation results

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Conclusions

- Maximum signal around 420 - 460 e⁻ when Σ
- Effect of spread of charge can be limited by increasing number of levels threshold
- Is there an ‘optimum’ thickness of epitaxial layer ?

Collection with different thicknesses

